

## PR1001 - PR1007 FAST RECOVERY RECTIFIER DIODES

VOLTAGE RANGE: 50 - 1000V CURRENT: 1.0 A

## **Features**

- Diffused Junction
- Fast Switching for High Efficiency
- High Current Capability and Low Forward Voltage Drop
- Surge Overload Rating to 30A Peak
- Low Reverse Leakage Current

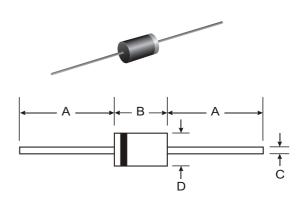
## **Mechanical Data**

- Case: D O 4 1 Molded Plastic
- Terminals: Plated Leads Solderable per

MIL-STD-202, Method 208

- Polarity: Cathode Band
- Weight: 0.34 grams (approx.)
- Mounting Position: Any
- Marking: Type Number





DO-41								
Dim	Min	Max						
Α	25.40	_						
В	4.06	5.21						
С	0.71	0.864						
D	2.00	2.72						
All Dimensions in mm								

## Maximum Ratings and Electrical Characteristics @ T<sub>A</sub> = 25°C unless otherwise specified

Single phase, half wave, 60Hz, resistive or inductive load. For capacitive load, derate current by 20%

Characteristic	Symbol	PR1001	PR1002	PR1003	PR1004	PR1005	PR1006	PR1007	Unit
Peak Repetitive Reverse Voltage Working Peak Reverse Voltage DC Blocking Voltage (Note 5)	V <sub>RRM</sub> V <sub>RWM</sub> V <sub>R</sub>	50	100	200	400	600	800	1000	V
RMS Reverse Voltage	V <sub>R(RMS)</sub>	35	70	140	280	420	560	700	V
Average Rectified Output Current (Note 1) @ T <sub>A</sub> = 55°C	Io	1.0					А		
Non-Repetitive Peak Forward Surge Current 8.3ms Single half sine-wave Superimposed on Rated Load	I <sub>FSM</sub>				30				А
Forward Voltage Drop @ I <sub>F</sub> = 1.0A	V <sub>FM</sub>	1.3					V		
		5.0 50						μA	
Reverse Recovery Time (Note 3)	t <sub>rr</sub>		1:	50		250	50	00	ns
Typical Total Capacitance (Note 2)		15 8					pF		
Typical Thermal Resistance Junction to Ambient		95						°C/W	
Operating and Storage Temperature Range		-65 to +150						°C	

Notes:

- 1. Valid provided that leads are maintained at ambient temperature at a distance of 9.5mm from the case.
- 2. Measured at 1.0MHz and applied reverse voltage of 4.0V DC.
- 3. Measured with  $I_F$  = 0.5A,  $I_R$  = 1.0A,  $I_{\Gamma\Gamma}$  = 0.25A. See figure 5.



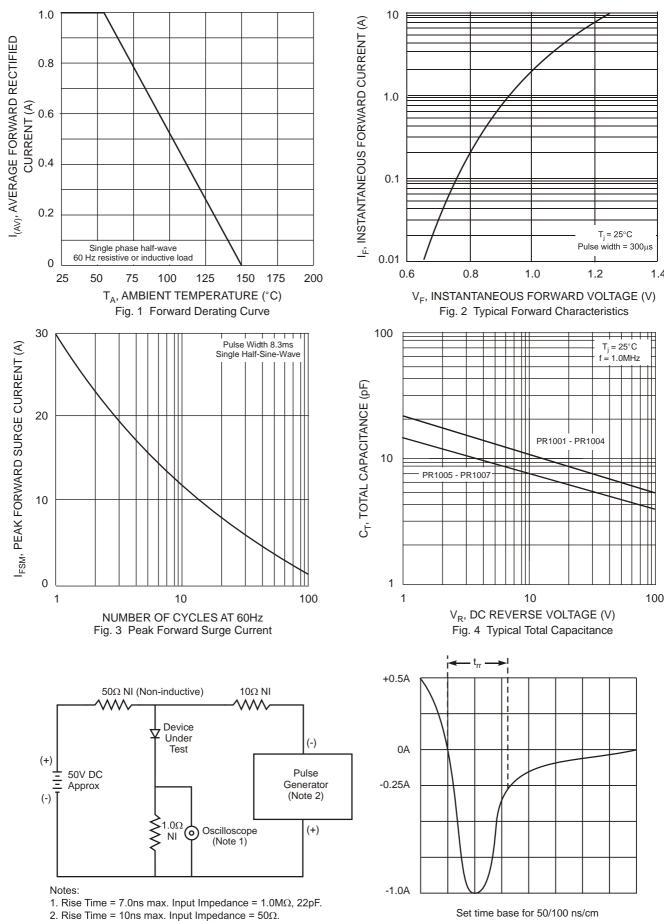


Fig. 5 Reverse Recovery Time Characteristic and Test Circuit